

Assessment of diagnostic test for automated bug localization

Tihhomirov, Valentin; Tšepurov, Anton; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [6] p. : ill

Automated design error debug using high-level decision diagrams and mutation operators

Raik, Jaan; Repinski, Urmis; Tšepurov, Anton; Hantson, Hanno; Ubar, Raimund-Johannes; Jenihhin, Maksim

Microprocessors and microsystems 2013 / p. 505-513 : ill <https://doi.org/10.1016/j.micpro.2012.11.004> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Model-based verification with error localization and error correction for C designs

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PSL assertion checkers synthesis with ASM based HLS tool ABELITE

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